

Test Report

HSI-CHIN ELECTRONICS CO., LTD.
 4F, NO. 194, SEC. 3, TA TUNG RD., HSI CHIH CITY,
 TAIPEI HSIEN, TAIWAN, R.O.C.

Report No. : CE/2006/13929
 Date : 2006/01/20
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The following merchandise was (were) submitted and identified by the client as :

Type of Product : TERMINAL: USB
Style/Item No : USB SERIES 全系列
Sample Received : 2006/01/13
Testing Date : 2006/01/13 TO 2006/01/20

Conclusion : The test results of Pb, Cd, Hg and Cr+6 for the submitted sample comply with the requirements of RoHS (2002/95/EC).


Test Result

PART NAME NO.1 : SILVER-GOLDEN COLORED METAL PIN

PASS

| Test Item (s): | Unit | Method | MDL | Result | Limit of ROHS |
|--------------------|------|--|-----|--------|---------------|
| | | | | No.1 | |
| Chromium VI (Cr+6) | ppm | UV-VIS after reference to US EPA 3060A. | 2 | N.D. | 1000 |
| Cadmium (Cd) | ppm | ICP-AES after reference to EN 1122, method B:2001 or other acid digestion. | 2 | N.D. | 100 |
| Mercury (Hg) | ppm | ICP-AES after reference to US EPA 3052 or other acid digestion. | 2 | N.D. | 1000 |
| Lead (Pb) | ppm | ICP-AES after reference to US EPA 3050B or other acid digestion. | 2 | 24.1 | 1000 |

NOTE: (1) N.D. = Not detected (<MDL)
 (2) ppm = mg/kg
 (3) MDL = Method Detection Limit


 Daniel Yeh, M.R. / Operation Manager
 Signed for and on behalf of
 SGS TAIWAN LTD.

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